

Resource Summary Report

Generated by [NIF](#) on Sep 15, 2026

FEI: Phenom XL SEM

RRID:SCR_019900

Type: Tool

Proper Citation

FEI: Phenom XL SEM (RRID:SCR_019900)

Resource Information

URL: <https://www.fei.com/products/sem/phenom-xl/>

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Description: Desktop scanning electron microscope with increased chamber size for large samples up to 100 mm x 100 mm.

Resource Type: instrument resource

Keywords: FEI, SEM, Instrument Equipment, USEDit,

Availability: Commercially available

Resource Name: FEI: Phenom XL SEM

Resource ID: SCR_019900

Alternate IDs: Model_Number_Phenom_XL

Record Creation Time: 20220129T080347+0000

Record Last Update: 20260912T195924+0000

Ratings and Alerts

No rating or validation information has been found for FEI: Phenom XL SEM.

No alerts have been found for FEI: Phenom XL SEM.

Data and Source Information

Source: [SciCrunch Registry](#)

Usage and Citation Metrics

We have not found any literature mentions for this resource.